

CLAIMS

Please amend the claims to read as indicated below.

1. (Currently Amended) An apparatus for debugging an imaging device, comprising:

an image view display for qualitatively displaying pixel characteristics in a first range of the imaging device; and

a code view display for quantitatively displaying numerical or symbolic data of individual pixels in a second range that is smaller than said first range and designated within an area displayed by said image view display, wherein said code view display comprises a code view and a marker display for indicating data shown at a central position in said code view display.

2. (Currently Amended) A semiconductor testing apparatus for testing an imaging device, comprising:

a test head for reading an output signal from an imaging device under test;

a memory which stores output data from said test head; and

an image processor which processes the output data stored in said memory;

wherein said image processor comprising:

a display unit for displaying data stored in said memory;

an input device which receives an operator's command;

wherein said image processor processes data stored in said memory means based on an operator's command received from said input device;

wherein said image processor comprises an image view display for qualitatively displaying pixel characteristics in a first range of the imaging device on said display unit according to an operator's command, and a code view display for quantitatively displaying on said display unit numerical or symbolic data of individual pixels in a second range that is smaller than said first range and designated in an area displayed by said image view display;

whereby data with respect to the pixel characteristics of the imaging device can be

displayed by said image view display or said code view display or both, wherein said code view display comprises a code view and a marker display for indicating data shown at a central position in said code view display.

3. (Original) A semiconductor testing apparatus according to claim 2, wherein said image view display comprises an image view, and an area display that indicates on the image view a code display area of the code view.

4. (Original) A semiconductor testing apparatus according to claim 2, wherein said code view display comprises a code view and a coordinate display for displaying the coordinates of data located at a central position in said code view display.

5. (Canceled)

6. (Currently Amended) A method of testing an imaging device, comprising the steps of:

retrieving output data from the imaging device as digital data;
qualitatively displaying the digital data as an image view in a first range of the imaging device;
accepting the designation of a second range that is smaller than said first range in the image view, which qualitatively displays digital data; and
quantitatively displaying characteristics of pixels in the imaging device within said second range with numerical or symbolic codes corresponding to a code view and a marker display for indicating data shown at a central position in said code display.

7. (Original) A method according to claim 6, wherein the step of retrieving output data from the imaging device comprises the step of processing the retrieved digital data.

8. (Currently Amended) A computer-readable recording medium storing a program for enabling a computer to function as:
an image view display for qualitatively displaying pixel characteristics in a first

range of an imaging device; and

a code view display for quantitatively displaying numerical or symbolic data of individual pixels in a second range that is smaller than said first range and designated within an area displayed by said image view display, wherein said code view display comprises a code view and a marker display for indicating data shown at a central position in said code view display.